### Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination SCHULIST ET AL. | Examiner | Art Unit | Page 1 of 3

### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,259,724 B1	07-2001	Esmailzadeh, Riaz	375/143
*	В	US-2001/0026543 A1	10-2001	Hwang et al.	370/335
*	С	US-6,480,525 B1	11-2002	Parsa et al.	375/141
*	D	US-6,507,601 B2	01-2003	Parsa et al.	375/141
*	E	US-2003/0048800 A1	03-2003	Kilfoyle et al.	370/441
*	F	US-6,549,525 B2	04-2003	Odenwalder, Joseph P.	370/332
*	G	US-6,587,447 B1	07-2003	Wang et al.	370/335
*	Н	US-6,594,248 B1	07-2003	Karna et al.	370/342
*	ı	US-2003/0142686 A1	07-2003	Kim, Joo-Deog	370/418
*	J	US-6,606,313 B1	08-2003	Dahlman et al.	370/347
*	К	US-6,650,629 B1	11-2003	Takahashi et al.	370/335
*	L	US-6,643,275 B1	11-2003	Gustafsson et al.	370/328
*	м	US-6,643,318 B1	11-2003	Parsa et al.	375/141

### FOREIGN PATENT DOCUMENTS

*	·	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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### NON-PATENT DOCUMENTS

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

## Notice of References Cited Application/Control No. 10/526,520 Examiner Hai V. Nguyen Applicant(s)/Patent Under Reexamination SCHULIST ET AL. Page 2 of 3

### **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,678,529 B1	01-2004	Moulsley et al.	455/522
*	В	US-2004/0132454 A1	07-2004	Trott et al.	455/447
*	С	US-6,859,445 B1	02-2005	Moon et al.	370/335
*	D	US-6,928,287 B2	08-2005	Trott et al.	455/447
*	Е	US-6,985,474 B2	01-2006	Dahlman et al.	370/347
*	F	US-6,992,998 B1	01-2006	Bhatoolaul et al.	370/329
*	G	US-7,058,038 B2	06-2006	Yi et al.	370/335
*	Н	US-7,076,262 B1	07-2006	Bhatoolaul et al.	455/522
*	ı	US-7,164,739 B1	01-2007	Trott, Mitchell D.	375/347
*	J	US-7,164,726 B1	01-2007	Trott, Mitchell D.	375/267
*	К	US-7,177,660 B2 ·	02-2007	Moulsley et al.	455/522
*	L	US-7,174,183 B2	02-2007	Moulsley et al.	455/522
*	М	US-7,209,515 B2	04-2007	Kilfoyle et al.	375/152

### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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### NON-PATENT DOCUMENTS

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

# Notice of References Cited Application/Control No. 10/526,520 Examiner Hai V. Nguyen Applicant(s)/Patent Under Reexamination SCHULIST ET AL. Art Unit Page 3 of 3

### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,209,709 B2	04-2007	Miyazaki et al.	455/67.11
*	В	US-7,254,413 B2	08-2007	Muller et al.	455/522
	С	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
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### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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### NON-PATENT DOCUMENTS

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.